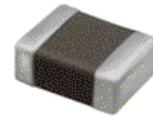


Metal Composite Type Power Inductor

Specification Sheet



CIGW252010EH4R7MNE (2520 / EIA 1008)



APPLICATION

Mobile Phones, LCD & AMOLED Display, HDD, SDD etc

FEATURES

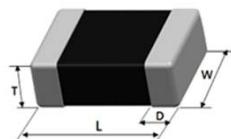
High Current Type
Low DC resistance
Magnetically shielded structure
Free of all RoHS-regulated substances
Monolithic structure for high reliability

RECOMMENDED LAND PATTERN



Unit : mm	
TYPE	2520
A	1.2
B	0.8
C	2.0

DIMENSION



TYPE	Dimension [mm]			
	L	W	T	D
2520	2.5±0.2	2.0±0.2	1.0 max	0.55±0.25

DESCRIPTION

Part no.	Size [inch/mm]	Thickness [mm] (max)	Inductance [uH]	Tolerance [%]	DC Resistance [mΩ]		Rated DC Current (Isat) [A]		Rated DC Current (Irms) [A]	
					Max.	Typ.	Max.	Typ.	Max.	Typ.
CIGW252010EH4R7MNE	1008/2520	1.0	4.7	±20%	150	130	1.9	2.2	1.4	1.6

* Inductance : Measured with a LCR meter 4991A(Agilent) or equivalent (Test Freq. 1MHz, Level 0.1V)

* DC Resistance : Measured with a Resistance HI-TESTER 3541(HIOKI) or equivalent

* Maximum allowable DC current : Value defined when DC current flows and the initial value of inductance has decreased by 30% or when current flows and temperature has risen to 40°C whichever is smaller. (Reference: ambient temperature is 25°C±10)

(Isat) : Allowable current in DC saturation : The DC saturation allowable current value is specified when the decrease of the initial inductance value at 30% (Reference: ambient temperature is 25°C±10)

(Irms) : Allowable current of temperature rise : The temperature rise allowable current value is specified when temperature of the inductor is raised 40°C by DC current. (Reference: ambient temperature is 25°C±10)

* Absolute maximum voltage : Absolute maximum voltage DC 40V.

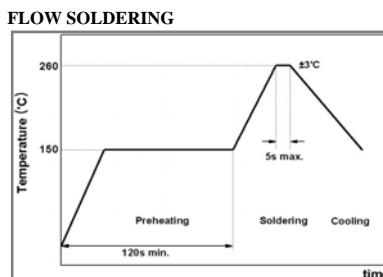
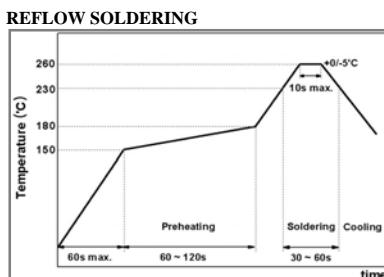
* Operating temperature range : -40 to +125°C (Including self-temperature rise)

PRODUCT IDENTIFICATION

CIG	W	2520	10	EH	4R7	M	N	E
(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)	(9)

- (1) Power Inductor
- (2) Type (W: Winding Type)
- (3) Dimension (2520: 2.5mm × 2.0mm)
- (4) Thickness (10: Max 1.0mm)
- (5) Remark (Characterization Code)
- (6) Inductance (4R7: 4.7uH)
- (7) Tolerance (M:±20%)
- (8) Internal Code
- (9) Packaging (C: Paper tape, E: Embossed tape)

RECOMMENDED SOLDERING CONDITION



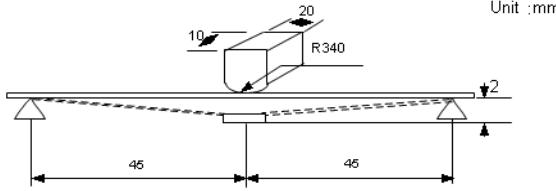
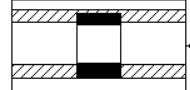
IRON SOLDERING

Temperature of Soldering Iron Tip	280°C max.
Preheating Temperature	150°C min.
Temperature Differential	$\Delta T \leq 130^\circ\text{C}$
Soldering Time	3sec max.
Wattage	50W max.

PACKAGING

Packaging Style	Quantity(pcs/reel)
Embossed Taping	3,000pcs

Reliability Test

Item	Specified Value	Test Condition				
Solderability	More than 90% of terminal electrode should be soldered newly.	After being dipped in flux for 4±1 seconds, and preheated at 150~180°C for 2~3 min, the specimen shall be immersed in solder at 245±5°C for 4±1 seconds.				
Resistance to Soldering	No mechanical damage. Remaining terminal Electrode: 75% min. Inductance change to be within ±20% to the initial.	After being dipped in flux for 4±1 seconds, and preheated at 150~180°C for 2~3 min, the specimen shall be immersed in solder at 260±5°C for 10±0.5 seconds.				
Thermal Shock (Temperature Cycle test)	No mechanical damage Inductance change to be within ±20% to the initial.	Repeat 100 cycles under the following conditions. -40±3°C for 30 min → 85±3°C for 30 min				
High Temp. Humidity Resistance Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, 85%RH, for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.				
Low Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Exposure at -55±2°C for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.				
High Temperature Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Exposure at 125±2°C for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.				
High Temp. Humidity Resistance Loading Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, 85%RH, Rated Current for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.				
High Temperature Loading Test	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, Rated Current for 500±12 hours. Measure the test items after leaving at normal temperature and humidity for 24 hours.				
Reflow Test	No mechanical damage Inductance change to be within ±20% to the initial	Peak 260±5°C, 3 times				
Vibration Test	No mechanical damage Inductance change to be within ±20% to the initial.	Solder the sample on PCB. Vibrate as apply 10~55Hz, 1.5mm amplitude for 2 hours in each of three(X,Y,Z) axis (total 6 hours).				
Bending Test	No mechanical damage	Bending Limit; 2mm Test Speed; 1.0mm/sec. Keep the test board at the limit point in 5 sec. PCB thickness : 1.6mm				
		 <p>Unit : mm</p>				
Terminal Adhesion Test	No indication of peeling shall occur on the terminal electrode.	<table border="1"> <tr> <td>W(kgf)</td> <td>TIME(sec)</td> </tr> <tr> <td>0.5</td> <td>10±1</td> </tr> </table>	W(kgf)	TIME(sec)	0.5	10±1
W(kgf)	TIME(sec)					
0.5	10±1					
						
Drop Test	No mechanical damage Inductance change to be within ±20% to the initial.	Random Free Fall test on concrete plate. 1 meter, 10 drops				
Ipeak (AC+DC Load Life)	No mechanical damage Inductance change to be within ±20% to the initial	85±2°C, 85%RH, Load(Ipeak) for 120 hours. (Frequency:1MHz, Load(Ipeak):1.5hr on / 0.5hr off) Measure the test items after leaving at normal temperature and humidity for 24 hours. * Load(Ipeak) = Irms(max)×1.4				



Metal Composite Type Power Inductor

Data Sheet



1. Model : CIGW252010EH4R7MNE

2. Description

Part no.	Size [inch/mm]	Thickness [mm] (max)	Inductance [uH]	Tolerance [%]	DC Resistance [mΩ]		Rated DC Current (Isat) [A]		Rated DC Current (Irms) [A]	
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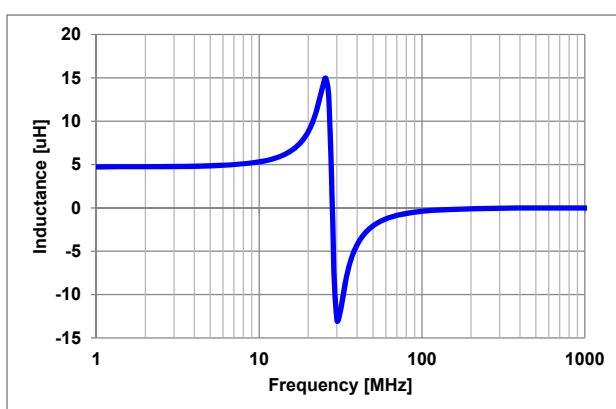
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* Operating temperature range : -40 to +125°C (Including self-temperature rise)

3. Characteristics data

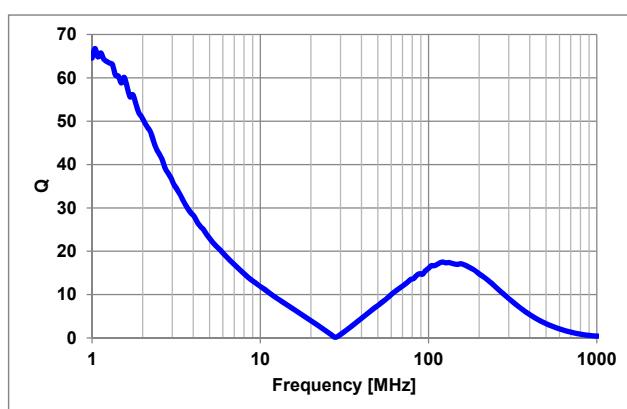
1) Frequency characteristics (Ls)

Agilent E4294A +E4991A , 1MHz to 1,000MHz

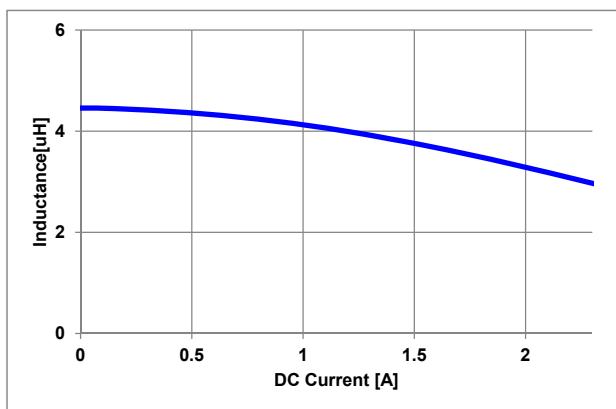


2) Frequency characteristics (Q)

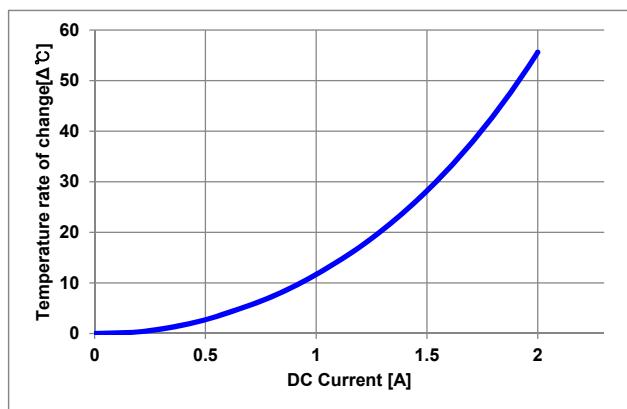
Agilent E4294A +E4991A , 1MHz to 1,000MHz



3) DC Bias characteristics (Typ.)



4) Temperature characteristics (Typ.)



Any data in this sheet are subject to change, modify or discontinue without notice

The data sheets include the typical data for design reference only. If there is any question regarding the data sheets, please contact our sales personnel or application engineers